

<b>Search Notes (continued)</b>	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/088,330	GOOD ET AL.
Examiner	Art Unit	
John Kim	1723	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

**Search Notes****Application/Control No.**

10/088,330

**Examiner**

John Kim

**Applicant(s)/Patent under Reexamination**

GOOD ET AL.

**Art Unit**

1723

**SEARCHED**

Class	Subclass	Date	Examiner
210	198.2, 263, 283, 287, 289, 290	1/17/2006	JK
	291, 435		
	446, 456		
	483, 484		
	488, 489		
	490, 491		
	502.1		
422	58, 59		
	60, 69		
	70, 101		
	102, 104		
436	177, 178		
	527		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor Name Search	1/17/2006	JK
EAST Search Note Attached	1/17/2006	JK